

10/694158

<b>FORM PTO-1449/A and B (Modified)</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				APPLICATION NO.: Unassigned		ATTY. DOCKET NO.: S1022.81058US00	
				FILING DATE: Herewith		CONFIRMATION NO.: Unassigned	
				APPLICANT: Luc WUIDART et al.			
				GROUP ART UNIT: Unassigned		EXAMINER: Unassigned	
Sheet	1	of	1				

#### U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
WZ	*	4,559,637		Weber	12/17/85
	*	5,418,738		Abadeer et al.	05/23/95
	*	4,399,372		Tanimoto et al.	08/16/83
	*	6,433,725		Chen et al.	08/13/02
	*	4,146,902		Tanimoto et al.	03/27/79
	*	4,586,163		Koike	04/29/86
	*	5,187,559		Isobe et al.	02/16/93
	*	4,698,589		Blankenship et al.	10/06/87
	*	US2002/0027793	A1	Johnson et al.	03/07/02

#### FOREIGN PATENT DOCUMENTS

Examiner's Initials	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/ Country	Number	Kind Code			
WZ		DE	101 01 575	A1	Infineon Technologies AG	07/25/02	N
		DE	198 39 141	A1	Philips Corporate Intellectual Property	03/02/00	N

#### OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials	Cite No	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
WZ		French Search Report from French Patent Application No. 02/13458, filed October 28, 2002	
		French Search Report from French Patent Application No. 02/13457, filed October 28, 2002	
		French Search Report from French Patent Application No. 02/13694, filed October 31, 2002	
		Kato K. et al. "A Physical Mechanism of Current-Induced Resistance Decrease In Heavily Doped Polysilicon Resistors" IEEE Transactions on Electron Devices, IEEE Inc. New York, US, vol. 29, no. 8, August 1982, pages 1156-1161	

EXAMINER	<i>WZ</i>	DATE CONSIDERED	09/10/04
----------	-----------	-----------------	----------

#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\* Pursuant to new U.S. PTO practice copies of any U.S. Patent are not enclosed.